Special Issue

Challenging Methods and Applications for Smart Measurement Using Machine Vision

Message from the Guest Editor

The widespread use of smart measures in several applications is the result of technological improvement. Machine vision (MV) is a technology and approach that enables automatic imaging-based inspection and analysis for a variety of industrial applications, including robot guidance and autonomous inspection. To enable measurements in each of these applications, sensors must be connected. Machine vision attempts to creatively combine already available technology and use them to address issues in the actual world. These kinds of technologies are becoming more prevalent in every aspect of daily life, including in the medical field, business, agriculture, smart cities, and smart health monitoring.
We seek contributions that cover the most recent developments in measuring and instrumentation science and technology as well as machine vision advancements related to production, the use of smart materials, and measurement and estimation methods, among others.

Guest Editor

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Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

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